
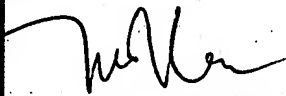


Issue Classification 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/765,311	WENDELL ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION										
ORIGINAL				CROSS REFERENCE(S)						
CLASS	SUBCLASS			CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
327	51			327	52	55	57			
INTERNATIONAL CLASSIFICATION										
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				3145						
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HIEP NGUYEN 02.04.06 (Assistant Examiner) (Date)		 TUAN T. LAM PRIMARY EXAMINER (Primary Examiner)		Total Claims Allowed: 22	
(Legal Instruments Examiner) (Date)		2/4/06 (Date)		O.G. Print Claim(s) 1	O.G. Print Fig. 28

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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